Future ATE: Perspectives & Requirements

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Today and for some time, both the user and supplier wings of the industry have speculated as to the proper form of ATE and its direction of evolution.

Trends can be difficult to predict accurately. This is partly because the constant changes in business, technology and decision criteria makes it difficult to concretely model the parts of the industry. Thus, the validity of a claim can change or require periodic refinement over time. Simply, the definitions and assumptions can be somewhat fluid until accepted by the marketplace.

Some of the claims that have concerned ATE related fields include:

- open architecture testers,
- the impact of contract manufacturing (outsourcing)
  - the approach to buying test time vs. testers,
- the impact of DFT in targeting "old" depreciated testers,
- the attractive cost vs. long term utilization of reduced feature or "DFT testers,"
- the role of niche instrumentation in future ATE form,
- the ability of ATE to provide value given that DFT works to curb the need for tester resources,
- whether or not the traditional ATE industry can continue to exist – if not, what could it look like
- and, of course, nobody likes paying for ATE

ITC provides a unique opportunity for ATE users to communicate with ATE providers, chip-houses and technology developers. The information exchange will certainly be valuable to ATE suppliers and technologists, as well as the consumers themselves who need to forward their business.

The panelists will present their perspectives on the state of the ATE/Test industry and how it needs to change. In addition, the panelists will outline their opinions concerning the kinds of business and technological concerns they would like the community to address.

Organizer: Fidel Muradali
Moderator: Gordon Robinson

Panelists: Tom Newsom – Agilent Technologies
John Roberts - STATS
Navid Shahriari- Intel
Lee Song - Teradyne
Don Wheater - IBM

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